

AIS-Q572

(With 3.5" SATA H.D)

Environment Test Report

Report NO: 11I020009

Summary	<p><input type="checkbox"/> Pass</p> <p><input type="checkbox"/> Fail</p> <p>Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.</p> <p><input checked="" type="checkbox"/> Pass with Deviation</p> <p>Comment: <u>Under PassMark Burn In Test 6.0 Pro , test COM port baud rate 115200 test fail , but change to 9600 test pass.</u></p>
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Issue date

Approval

Test Engineer

2011-05-11

Jansin Lee

Clement Chien

Test item list

1.	<i>Test item list</i> -----	2
2.	<i>Configuration of EUT</i> -----	3
2.	<i>Temperature rise test</i> -----	4
3.	<i>Temperature cycle operation test</i> -----	8
4.	<i>High temperature storage test</i> -----	9
5.	<i>Low temperature storage test</i> -----	10
6.	<i>Humidity test</i> -----	11
7.	<i>Cold start and hot start test</i> -----	12

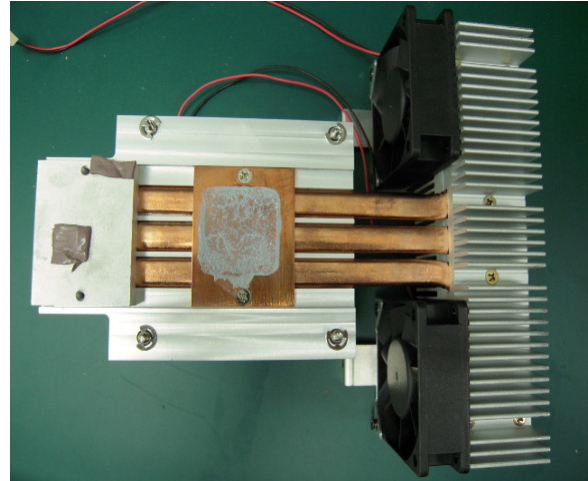
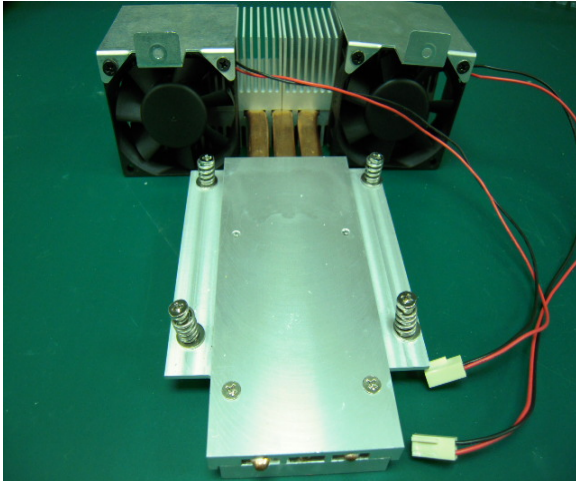
Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

Configuration of EUT

Num	Item	Spec
1.	System:	AIS-Q572
	1. Main Board	IMBI-QM57 A0.5 (BIOS Ver : AIS-Q572 0.03 X64)
	2. CPU	Intel Core i7-860 Processor 2.80 GHz
	3. Memory	Transcend 4GB*2 / DDR3 1333 CL9
	4. 3.5" SATA HDD	Seagate ST380815AS/80GB
	5. Test Software	Windows XP / Run PassMark Burn In Test 6.0 Pro
	6.VGA Card	ASUS ENGT220/1GD2/A
	7.DVD-ROM	SONY AD-7585H
2.	ATX Power Supply	CWT PSM275H 275W

Heat-Pipe



Temperature rise test

Test Date: 04-12-2011

Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

Test Standard: Reference EN 61131-2(94), UL508 (94)

Temperature Measurement:

40 Channel Thermal Recorder:

YOKOGAWA Inc,

Model: DA100-13-1D

Date of Calibration: 11/08/2010

Serial Number: 12A323190

Test Condition:

Ambient temperature: 45°C

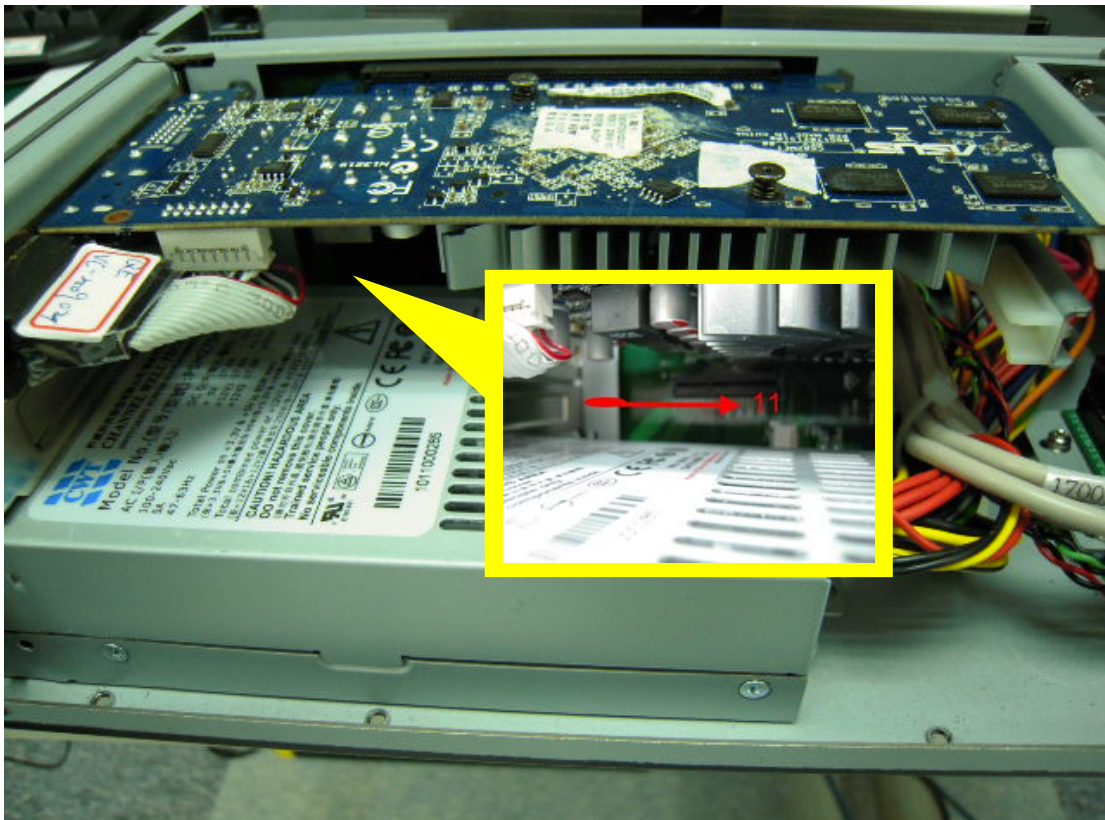
Continuous running till thermal stability (within less than 1°C)

Test Software:

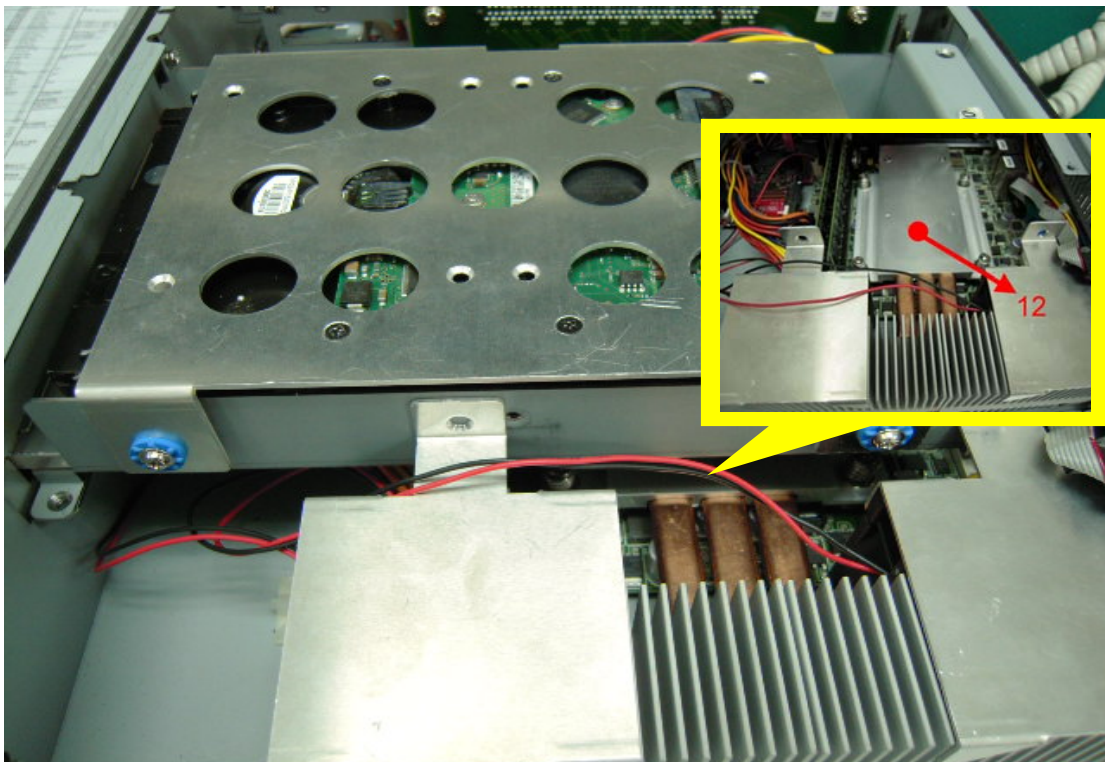
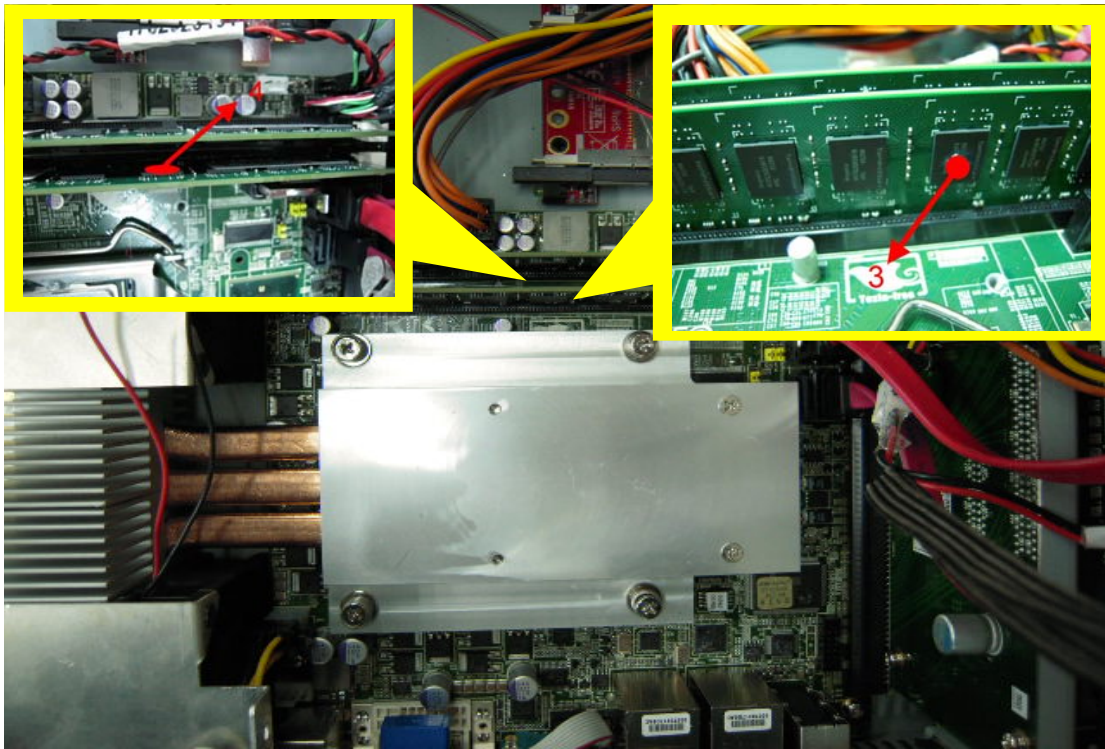
Windows XP / Run PassMark Burn In Test 6.0 Pro

Terminal Recorder:

Measuring Thermal Couple Position :



Temperature rise test



Temperature rise test



Temperature rise test

Thermal profile data:

AIS-Q572

Point	Temp. Stage(°C)	Spec	45	25
IMBI-QM57				
01. CPU - Intel Core i7-860 Processor 2.80GHz		72.7	70.3	50.3
02. U13 - (TF)Chipset Ibex Peak PCH951P.INTEL.BD82Q57,SLGZW		111	65.8	45.5
03. RAM - Transcend 4GB*2 / DDR3 1333 CL9		95	55.1	35.1
04. RAM - Transcend 4GB*2 / DDR3 1333 CL9		95	54.0	34.0
05. SATA H.D - Seagate ST380815AS/80GB		60	55.7	35.7
06. U15 - (TF) Super I/O.ITE.IT8718F/HX-L		100	59.2	39.2
07.U19 - (TF) 7.1Channel HDAudio Codec.REALTEK.ALC888-VC2-GR		100	66.5	46.5
08.U18 - (TF)GigaBit Ethernet Chipset.Intel.WG82574L.WG82574L SLBA8		109	60.7	40.7
09.U20 - (TF)SPI Bus Serial EEPROM.ATMEL.AT25080AN-10SU-2.7		115	58.3	38.3
10.U12. -(TF) 4Phase PWM Controler.Intersil.ISL6334CRZ		100	60.7	40.7
11. Control Box Inside Air Temperature		N/A	48.5	28.5
12. Control Box Inside Air Temperature		N/A	50.5	30.5
13. Control Box Surface Temperature		N/A	50.2	30.2
14. Chamber Air Temperature		N/A	45.2	25.2
Any Tm value showed in red words which meaning the value over the Tc degree C of this device specification.				

Temperature Measurement Table:

Location	TA=45.2°C	Temp. Rise (Thermal Couple)	SpeedFan 4.42 (Read from BIOS)
Sensor 1 / Temp.(CPU)		70.3°C	84.0°C
Sensor 2 / Temp1.(South Bridge)		65.8°C	71.0°C
Sensor 3 / Temp2.(System)		N/A	64.0°C

Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q572)

Test Result:

No problem was found during the temperature rise operation test.

Temperature cycle test

Test Date: 04-06 ~ 08-2011

Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

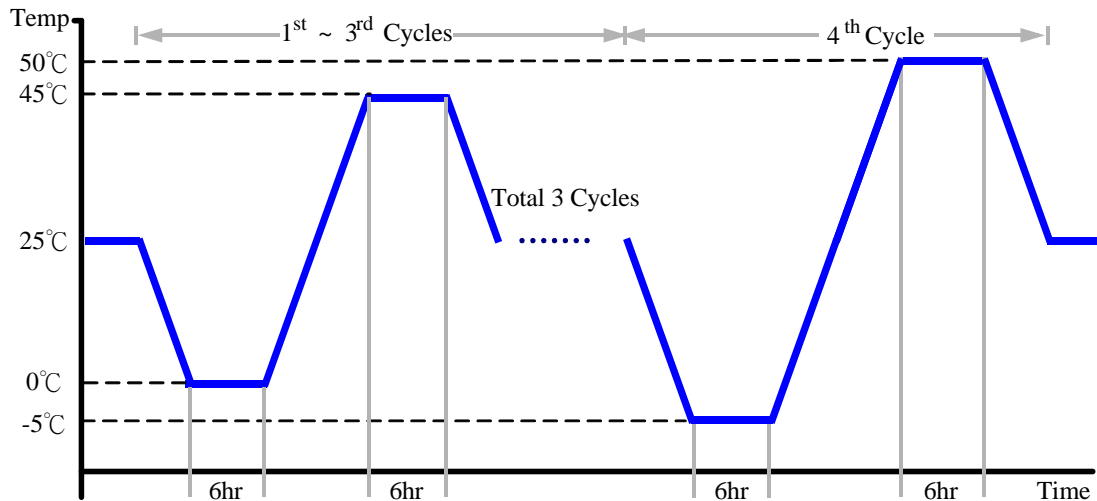
Test Standard: Reference IEC68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.
Model: THS-D75-100+LN2
Date of Calibration: 12/02/10
Serial Number: 6487KT

Test Condition:

1. Test Low Temperature: 0°C (1~3 cycles)
-5°C (4th cycle)
2. Test High Temperature: 45°C (1~3 cycles)
50°C (4th cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q572)

Test Result:

No problem was found during the temperature operation cycle test.

High temperature storage test

Test Date: 03-30-2011 ~ 04-01-2011

Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-2 Testing procedures
Test Bb: Dry Heat Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

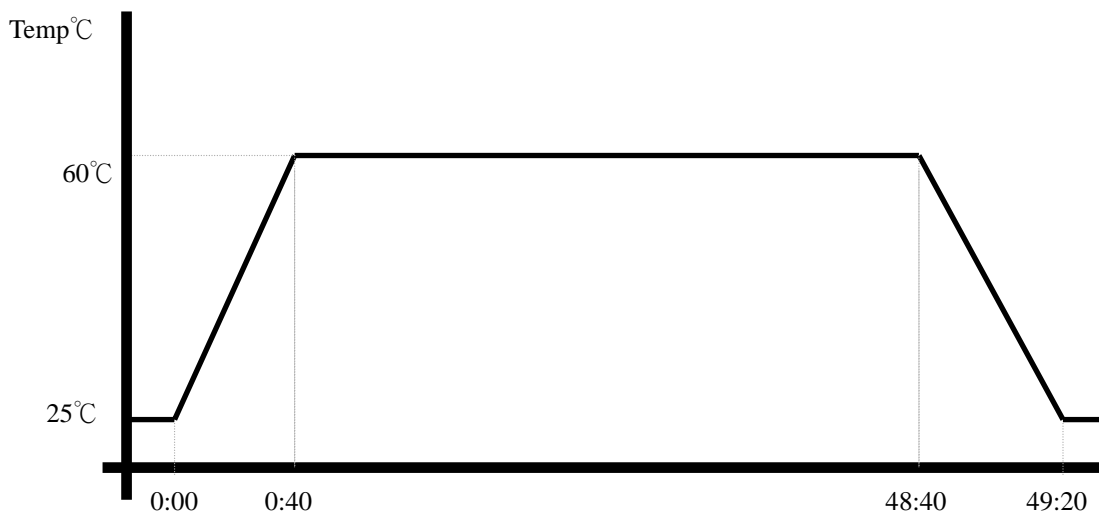
Model: THS-D75-100+LN2

Date of Calibration: 12/02/10

Serial Number: 6487KT

Testing Item:

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q572)

Test Result:

No problem was found after the high temperature storage test.

Low temperature storage test

Test Date: 03-28 ~ 30-2011

Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-1 Testing procedures
Test Ab: Cold Test (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber
K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

Date of Calibration: 12/02/10

Serial Number: 6487KT

Testing Item:

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
4. Test Environment Curve:



Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q572)

Test Result:

No problem was found after the low temperature storage test.

Humidity test

Test Date: 04-03 ~ 05-2011

Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-3 Testing procedures
Test Ca: Damp heat, steady state (Non-operation)

Test Equipment:

Programmable Temperature & Humidity Chamber

K.SON. INS. TECH. CORP.

Model: THS-D75-100+LN2

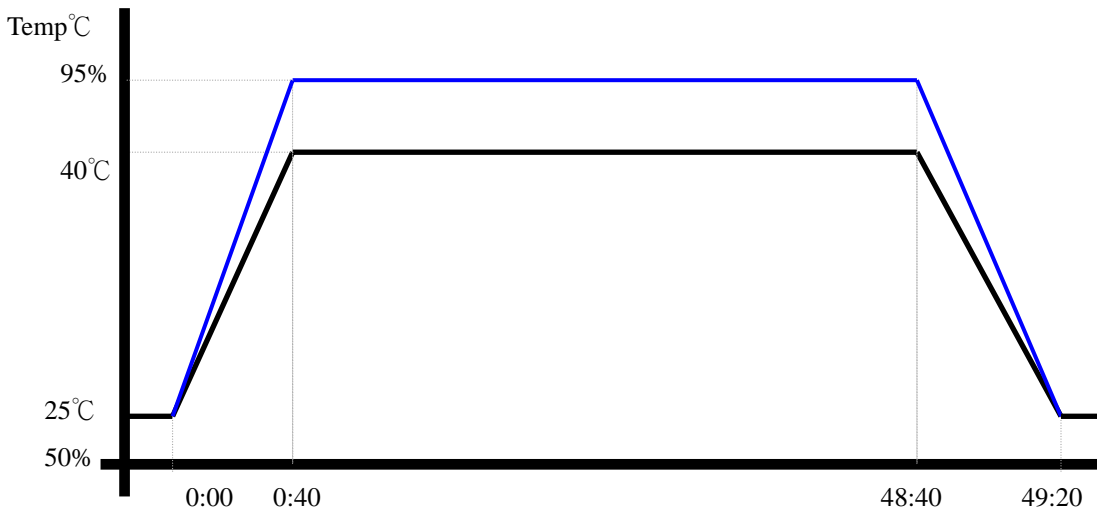
Date of Calibration: 12/02/10

Serial Number: 6487KT

Testing Item:

1. Test Temperature: 40°C
2. Test Humidity: 95%RH
3. Test Times: 48Hrs
4. Test Software: Windows XP / Run PassMark Burn In Test 6.0 Pro
5. Test Environment Curve:

Humidity %



Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-Q572)

Test Result:

No problem was found after the humidity storage test.

Cold start and hot start test

Test Date: 04-05 ~ 06-2011

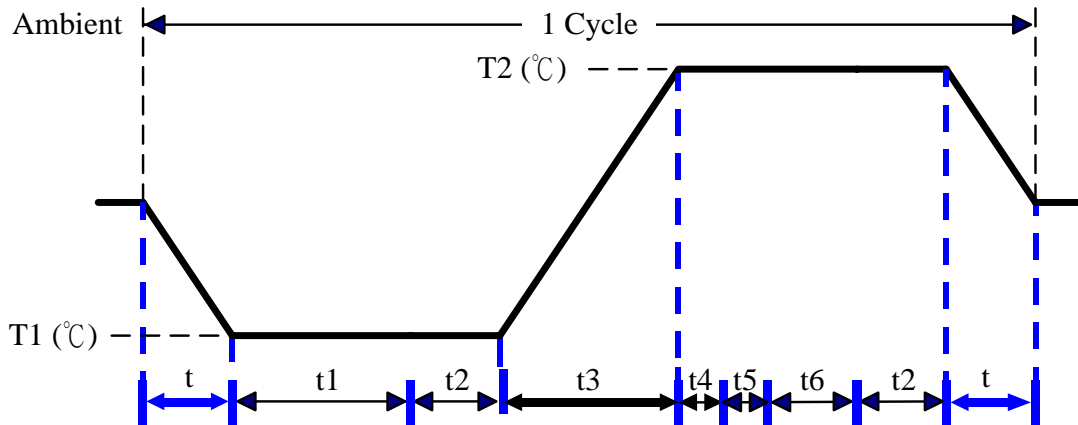
Test Product: AIS-Q572

Test Site: AAEON QE Internal Lab.

Test Standard: Reference IEC 68-2-14 Testing procedures
Test N: Change of temperature Test

Test Equipment:
 Programmable Temperature & Humidity Chamber
 K.SON. INS. TECH. CORP.
 Model: THS-D75-100+LN2
 Date of Calibration: 12/02/10
 Serial Number: 6487KT

Test Condition:



Parameters	Description
T1	-5°C
T2	50°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temperature slope
 t, t1, t6: Power Off
 t2: Power on/off test 10 times (on 2 min / off 5min)
 t3, t4: Run PassMark Burn In Test
 t5: Win XP Software restart test 3 times
 Test Software: Windows XP

Test Result:

- a. No problem was found during the cold start test.
- b. No problem was found during the hot start test.